

# SN54HC367, SN74HC367 HEX BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

SCLS309B – JANUARY 1996 – REVISED MAY 1997

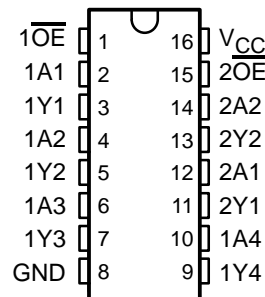
- High-Current 3-State Outputs Drive Bus Lines, Buffer Memory Address Registers, or Drive up to 15 LSTTL Loads
- True Outputs
- Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

## description

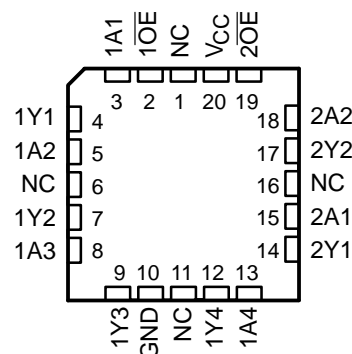
These hex buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The 'HC367 are organized as dual 4-line and 2-line buffers/drivers with active-low output-enable ( $\overline{1OE}$  and  $\overline{2OE}$ ) inputs. When  $\overline{OE}$  is low, the device passes noninverted data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

The SN54HC367 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . The SN74HC367 is characterized for operation from  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ .

SN54HC367 . . . J OR W PACKAGE  
SN74HC367 . . . D OR N PACKAGE  
(TOP VIEW)



SN54HC367 . . . FK PACKAGE  
(TOP VIEW)



NC – No internal connection

FUNCTION TABLE  
(each buffer/driver)

INPUTS		OUTPUT
$\overline{OE}$	A	Y
H	X	Z
L	H	H
L	L	L



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS  
INSTRUMENTS**

POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

Copyright © 1997, Texas Instruments Incorporated

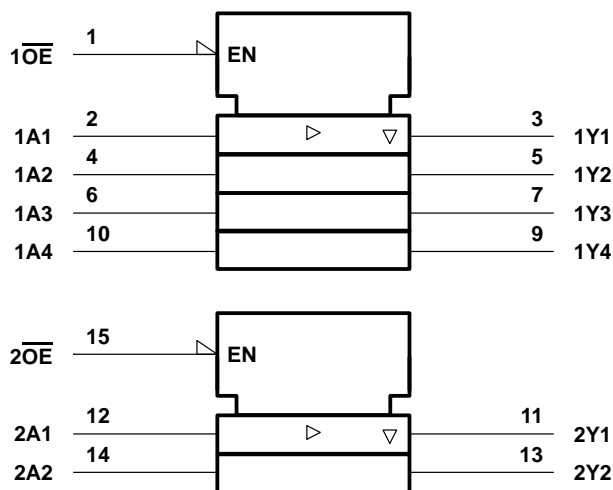
# SN54HC367, SN74HC367

## HEX BUFFERS AND LINE DRIVERS

### WITH 3-STATE OUTPUTS

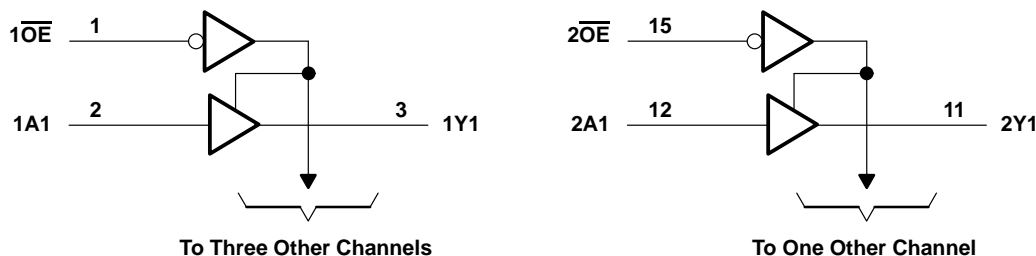
SCLS309B – JANUARY 1996 – REVISED MAY 1997

#### logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.  
Pin numbers shown are for the D, J, N, and W packages.

#### logic diagram (positive logic)



Pin numbers shown are for the D, J, N, and W packages.

#### absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, $V_{CC}$	–0.5 V to 7 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see Note 1)	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ ) (see Note 1)	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±35 mA
Continuous current through $V_{CC}$ or GND	±70 mA
Package thermal impedance, $\theta_{JA}$ (see Note 2): D package	113°C/W
N package	78°C/W
Storage temperature range, $T_{stg}$	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.  
2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

# SN54HC367, SN74HC367 HEX BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

SCLS309B – JANUARY 1996 – REVISED MAY 1997

## recommended operating conditions

			SN54HC367			SN74HC367			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage		2	5	6	2	5	6	V
V <sub>IH</sub>	High-level input voltage	V <sub>CC</sub> = 2 V	1.5			1.5			V
		V <sub>CC</sub> = 4.5 V	3.15			3.15			
		V <sub>CC</sub> = 6 V	4.2			4.2			
V <sub>IL</sub>	Low-level input voltage	V <sub>CC</sub> = 2 V	0			0			V
		V <sub>CC</sub> = 4.5 V	0			1.35			
		V <sub>CC</sub> = 6 V	0			1.8			
V <sub>I</sub>	Input voltage		0			V <sub>CC</sub>			V
V <sub>O</sub>	Output voltage		0			V <sub>CC</sub>			V
t <sub>t</sub>	Input transition (rise and fall) time	V <sub>CC</sub> = 2 V	0			1000			ns
		V <sub>CC</sub> = 4.5 V	0			500			
		V <sub>CC</sub> = 6 V	0			400			
T <sub>A</sub>	Operating free-air temperature		−55			125			°C

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V <sub>CC</sub>	T <sub>A</sub> = 25°C			SN54HC367		SN74HC367		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V <sub>OH</sub>	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = –20 µA	2 V	1.9	1.998		1.9		1.9		V
			4.5 V	4.4	4.499		4.4		4.4		
			6 V	5.9	5.999		5.9		5.9		
		I <sub>OH</sub> = –6 mA	4.5 V	3.98	4.3		3.7		3.84		
		I <sub>OH</sub> = –7.8 mA	6 V	5.48	5.8		5.2		5.34		
V <sub>OL</sub>	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20 µA	2 V		0.002	0.1		0.1		0.1	V
			4.5 V		0.001	0.1		0.1		0.1	
			6 V		0.001	0.1		0.1		0.1	
		I <sub>OL</sub> = 6 mA	4.5 V		0.17	0.26		0.4		0.33	
		I <sub>OL</sub> = 7.8 mA	6 V		0.15	0.26		0.4		0.33	
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or 0		6 V		±0.1	±100		±1000		±1000	nA
I <sub>OZ</sub>	V <sub>O</sub> = V <sub>CC</sub> or 0		6 V		±0.01	±0.5		±10		±5	µA
I <sub>CC</sub>	V <sub>I</sub> = V <sub>CC</sub> or 0, I <sub>O</sub> = 0		6 V			8		160		80	µA
C <sub>i</sub>			2 V to 6 V		3	10		10		10	pF

# SN54HC367, SN74HC367

## HEX BUFFERS AND LINE DRIVERS

### WITH 3-STATE OUTPUTS

SCLS309B – JANUARY 1996 – REVISED MAY 1997

switching characteristics over recommended operating free-air temperature range,  $C_L = 50$  pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC}$	$T_A = 25^\circ\text{C}$			SN54HC367		SN74HC367		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
$t_{pd}$	A	Y	2 V		50	95		145		120	ns
			4.5 V		12	19		29		24	
			6 V		10	16		25		20	
$t_{en}$	$\overline{OE}$	Y	2 V		100	190		285		238	ns
			4.5 V		26	38		57		48	
			6 V		21	32		48		41	
$t_{dis}$	$\overline{OE}$	Y	2 V		50	175		265		240	ns
			4.5 V		21	35		53		48	
			6 V		19	30		45		41	
$t_t$		Any	2 V		28	60		90		75	ns
			4.5 V		8	12		18		15	
			6 V		6	10		15		13	

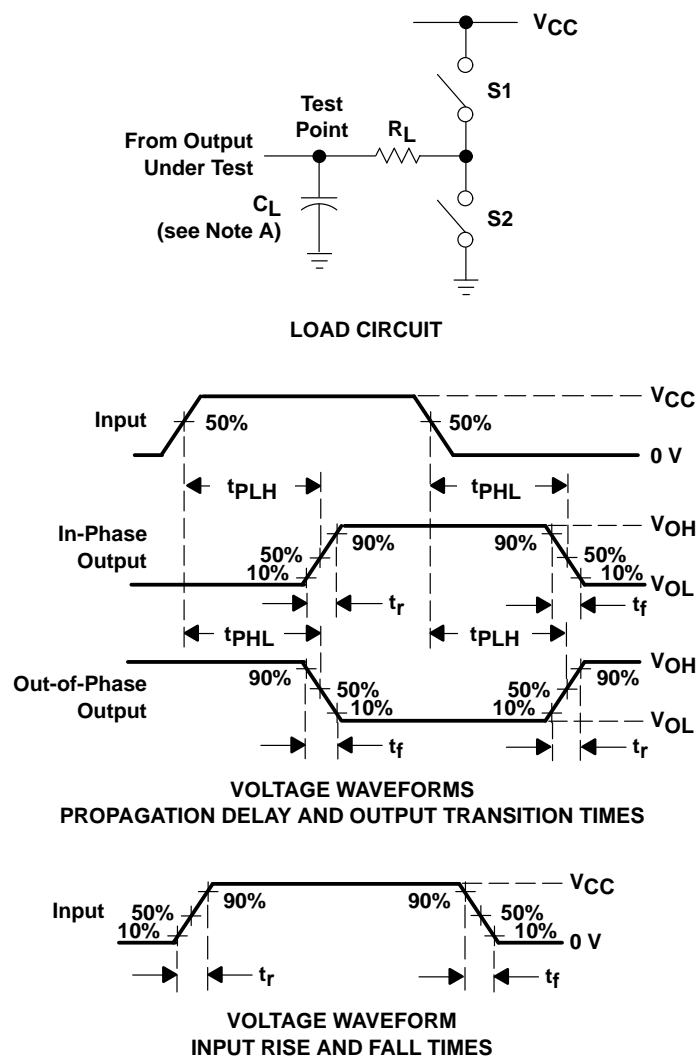
switching characteristics over recommended operating free-air temperature range,  $C_L = 150$  pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC}$	$T_A = 25^\circ\text{C}$			SN54HC367		SN74HC367		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
$t_{pd}$	A	Y	2 V		70	120		180		150	ns
			4.5 V		17	24		36		30	
			6 V		14	20		31		25	
$t_{en}$	$\overline{OE}$	Y	2 V		140	230		345		285	ns
			4.5 V		30	46		69		57	
			6 V		28	39		59		48	
$t_t$		Any	2 V		45	210		315		265	ns
			4.5 V		17	42		63		53	
			6 V		13	36		53		45	

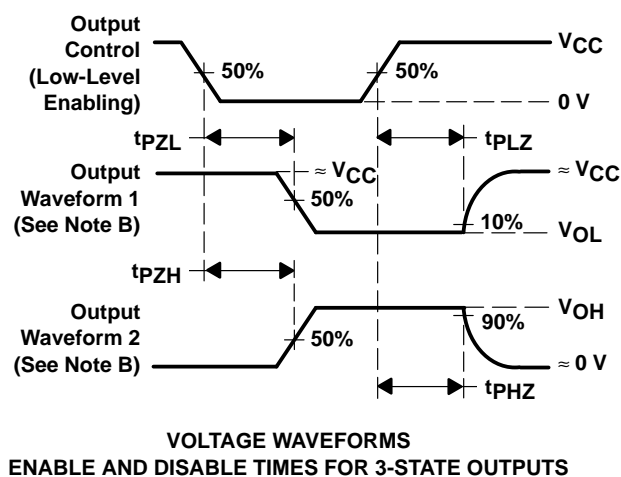
operating characteristics,  $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	TYP	UNIT
$C_{pd}$	Power dissipation capacitance per buffer/driver	No load	35	pF

## PARAMETER MEASUREMENT INFORMATION



PARAMETER	$R_L$	$C_L$	S1	S2
$t_{en}$	1 k $\Omega$	50 pF or 150 pF	Open	Closed
			Closed	Open
$t_{dis}$	1 k $\Omega$	50 pF	Open	Closed
			Closed	Open
$t_{pd}$ or $t_t$	—	50 pF or 150 pF	Open	Open



- NOTES:
- A.  $C_L$  includes probe and test-fixture capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 1$  MHz,  $Z_O = 50 \Omega$ ,  $t_r = 6$  ns,  $t_f = 6$  ns.
  - D. The outputs are measured one at a time with one input transition per measurement.
  - E.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .
  - F.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
  - G.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .

Figure 1. Load Circuit and Voltage Waveforms

## **IMPORTANT NOTICE**

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

**TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.**

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.